



# **PRODUCT DATA SHEET**



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Datasheet

es Samples

Please note: Please check the JINGAO Semiconductor website to verify the updated device numbers. The most current and up-to-date ordering information can be found at www.jg-semi.cn. Please email any questions regarding the system integration to JINGAO\_questions@jgsemi.com.

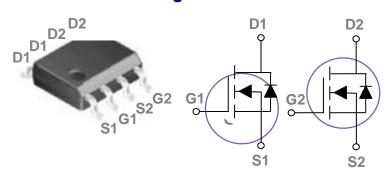




## **General Description**

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

## **Dual SOP8 Pin Configuration**



BVDSS	RDSON	ID
30V	32m $Ω$	5.3A

#### **Features**

- $30V, 5.3A, RDS(ON) = 32m\Omega @VGS = 10V$
- Improved dv/dt capability
- Fast switching
- 100% EAS Guaranteed
- Green Device Available

### **Applications**

- MB / VGA / Vcore
- POL Applications
- SMPS 2<sup>nd</sup> SR

### Absolute Maximum Ratings Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	30	V
V <sub>G</sub> S	Gate-Source Voltage	±20	V
1_	Drain Current – Continuous (T <sub>A</sub> =25°C)	5.3	Α
ID	Drain Current – Continuous (T <sub>A</sub> =70°C)	4.2	Α
I <sub>DM</sub>	Drain Current – Pulsed <sup>1</sup>	21.2	Α
EAS	Single Pulse Avalanche Energy <sup>2</sup>	5	mJ
IAS	Single Pulse Avalanched Current <sup>2</sup>	10	Α
Po	Power Dissipation (T <sub>A</sub> =25°C)	1.47	W
FD	Power Dissipation – Derate above 25°C	0.012	W/°C
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		85	°C/W



## **Electrical Characteristics** (T<sub>J</sub>=25 °C, unless otherwise noted)

### **Off Characteristics**

Symbol	DI Parameter Conditions		Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	BV <sub>DSS</sub> Drain-Source Breakdown Voltage V <sub>GS</sub> =0V , I <sub>D</sub> =250uA		30			V
△BV <sub>DSS</sub> /△T <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =1mA		0.018		V/°C
I <sub>DSS</sub>	Dunin Course Leakens Current	$V_{DS}$ =30V , $V_{GS}$ =0V , $T_{J}$ =25 $^{\circ}$ C			1	uA
	Drain-Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			10	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}=\pm 20V$ , $V_{DS}=0V$			±100	nA

#### **On Characteristics**

R <sub>DS(ON)</sub> Static Drain-Sou	Static Drain-Source On-Resistance <sup>3</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =3A		25	32	mΩ
	Static Diam-Source On-Nesistance	V <sub>GS</sub> =4.5V , I <sub>D</sub> =2A		43	52	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA		1.5	2.2	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient			-3.2		mV/°C
gfs	Forward Transconductance	$V_{DS}$ =10V , $I_{D}$ =3A		2.3		S

## **Dynamic and switching Characteristics**

Qg	Total Gate Charge <sup>3,4</sup>		 3.1	6.4	
$Q_{gs}$	Gate-Source Charge <sup>3, 4</sup> V <sub>DS</sub> =24V , V <sub>GS</sub> =10V , I <sub>D</sub> =2A		 0.1	0.5	nC
$Q_gd$	Gate-Drain Charge <sup>3, 4</sup>		 1.7	3.4	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>3,4</sup>		 2.2	4.5	
Tr	Rise Time <sup>3, 4</sup>	$V_{DD}$ =24 $V$ , $V_{GS}$ =10 $V$ , $R_{G}$ =6 $\Omega$	 6.9	13.8	no
$T_{d(off)}$	Turn-Off Delay Time <sup>3,4</sup>	I <sub>D</sub> =1A	 15.2	30.4	ns
Tf	Fall Time <sup>3, 4</sup>		 4.5	9	
Ciss	Input Capacitance		 245	490	
Coss	Output Capacitance	$V_{DS}$ =25V , $V_{GS}$ =0V , $F$ =1MHz	 40	80	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		 78	158	
Rg	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz	 0.9	1.8	Ω

### **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Conditions		Тур.	Max.	Unit
Is	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			5.3	Α
I <sub>SM</sub>	Pulsed Source Current <sup>3</sup>	VG=VD=UV, FOICE Current			10.6	Α
V <sub>SD</sub>	Diode Forward Voltage <sup>3</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1	V

#### Note:

- 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- 2.  $V_{DD}$ =25V, $V_{GS}$ =10V,L=0.1mH, $I_{AS}$ =10A., $R_{G}$ =25 $\Omega$ , Starting  $T_{J}$ =25 $^{\circ}$ C.
- 3. The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%.
- 4. Essentially independent of operating temperature.



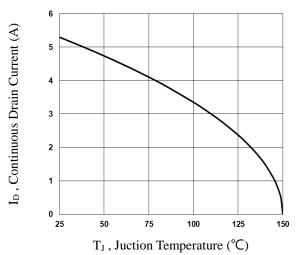


Fig.1 Continuous Drain Current vs. T<sub>c</sub>

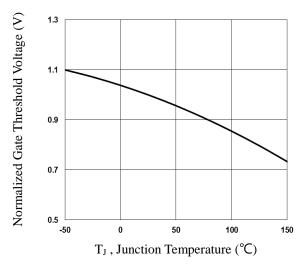


Fig.3 Normalized V<sub>th</sub> vs. T<sub>J</sub>

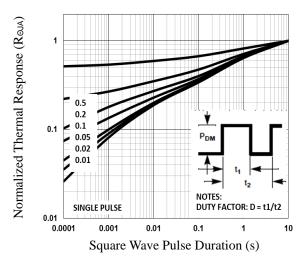


Fig.5 Normalized Transient Response

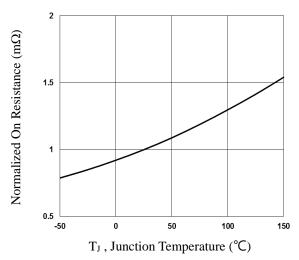


Fig.2 Normalized RDSON vs. T<sub>J</sub>

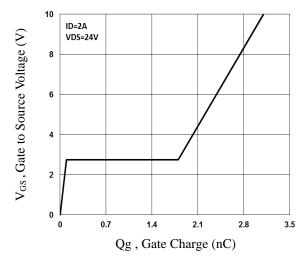


Fig.4 Gate Charge Waveform

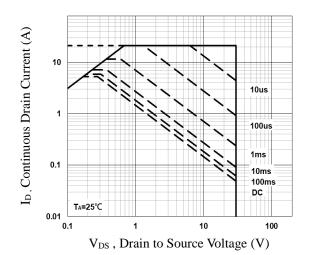
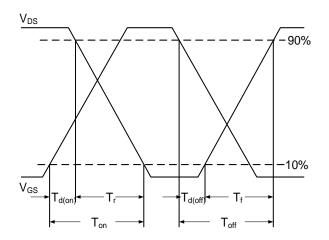


Fig.6 Maximum Safe Operation Area





# **ZXMN3A06DN8TA**



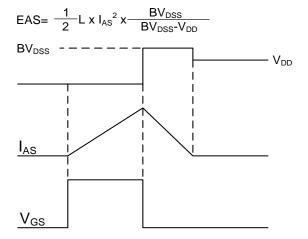
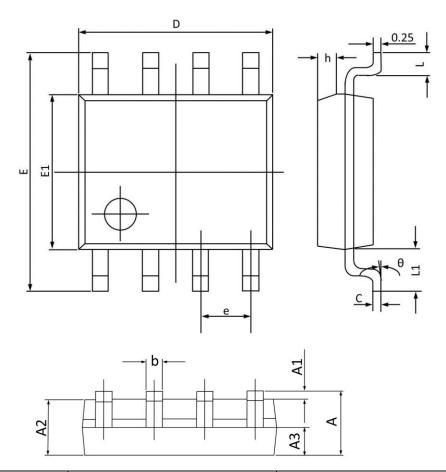


Fig.7 Switching Time Waveform

Fig.8 EAS Waveform



# **SOP8 PACKAGE INFORMATION**



Crmbol	Dimensions I	n Millimeters	Dimension	s In Inches
Symbol	Min	Max	Min	Max
A	1.350	1.750	0.053	0.068
A1	0.100	0.250	0.004	0.009
A2	1.300	1.500	0.052	0.059
A3	0.600	0.700	0.024	0.027
b	0.390	0.480	0.016	0.018
с	0.210	0.260	0.009	0.010
D	4.700	5.100	0.186	0.200
E	5.800	6.200	0.229	0.244
<b>E</b> 1	3.700	4.100	0.146	0.161
e	1.270	(BSC)	0.050	(BSC)
h	0.250	0.500	0.010	0.019
L	0.500	0.800	0.019	0.031
L1	1.0500	(BSC)	0.041(BSC)	
$\theta$	<b>0</b> °	8°	0°	8°

## **ZXMN3A06DN8TA**



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